Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/662,819	EBE ET AL.	
Examiner	Art Unit	_
Dana Farahani	2891	

	SEARCHED					
Class	Subclass	Date	Examiner			
257	14	5/11/2005	DF			
II.	15	5/11/2005	DF			
11	16	5/11/2005	DF			
0	17	5/11/2005	DF			
"	18	5/11/2005	DF			
111	19	5/11/2005	DF			
"	23	5/11/2005	DF			
"	25	5/11/2005	DF			
438	962	5/21/2005	DF			
977	DIG 1	5/21/2005	DF			

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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	•	, 				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
"257"/\$.ccls. and (quantum adj dot\$1) and (InGaAsP or InAlGaAs or InAlGaP)	5/11/2005	df		
"257"/\$.ccls. and (quantum adj dot\$1) and (InGaAsP)	5/11/2005	DF		
257/14-26. and (InGaAsP)	5/11/2005	DF		
257/14-26. and (InGaAsP or InAlGaAs or InAlGaP)	5/11/2005	DF		
quantum adj dot\$1	5/11/2005	DF		
(nano\$1particle\$1 or nano\$1dot\$1 or (artificial adj atom) or (dimensional adj dot))	5/21/2005	DF		
((quantum adj dot\$1) and ((increas\$3 or decreas\$3) with (concentration or composition)))	5/21/2005	DF		
((quantum adj dot\$1) and ((increas\$3 or decreas\$3 or gradual\$3) with (co	5/21/2005	DF		